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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	84MHz
Connectivity	I²C, IrDA, LINbus, SDIO, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	81
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f401vet6

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Table 2. STM32F401xD/xE features and peripheral counts

Peripherals		STM32F401xD			STM32F401xE		
Flash memory in Kbytes		384			512		
SRAM in Kbytes	System	96					
Timers	General-purpose	7					
	Advanced-control	1					
Communication interfaces	SPI/ I^2S	3/2 (full duplex)		4/2 (full duplex)	3/2 (full duplex)		4/2 (full duplex)
	I^2C	3					
	USART	3					
	SDIO	-	1		-	1	
USB OTG FS		1					
GPIOs		36	50	81	36	50	81
12-bit ADC		1					
Number of channels		10	16		10	16	
Maximum CPU frequency		84 MHz					
Operating voltage		1.7 to 3.6 V					
Operating temperatures		Ambient temperatures: –40 to +85 °C/–40 to +105 °C					
		Junction temperature: –40 to + 125 °C					
Package		WLCSP49 UFQFPN48	LQFP64	UFBGA100 LQFP100	WLCSP49 UFQFPN48	LQFP64	UFBGA100 LQFP100

2.1 Compatibility with STM32F4 series

The STM32F401xD/xE are fully software and feature compatible with the STM32F4 series (STM32F42x, STM32F43x, STM32F41x, STM32F405 and STM32F407)

The STM32F401xD/xE can be used as drop-in replacement of the other STM32F4 products but some slight changes have to be done on the PCB board.

Figure 1. Compatible board design for LQFP100 package

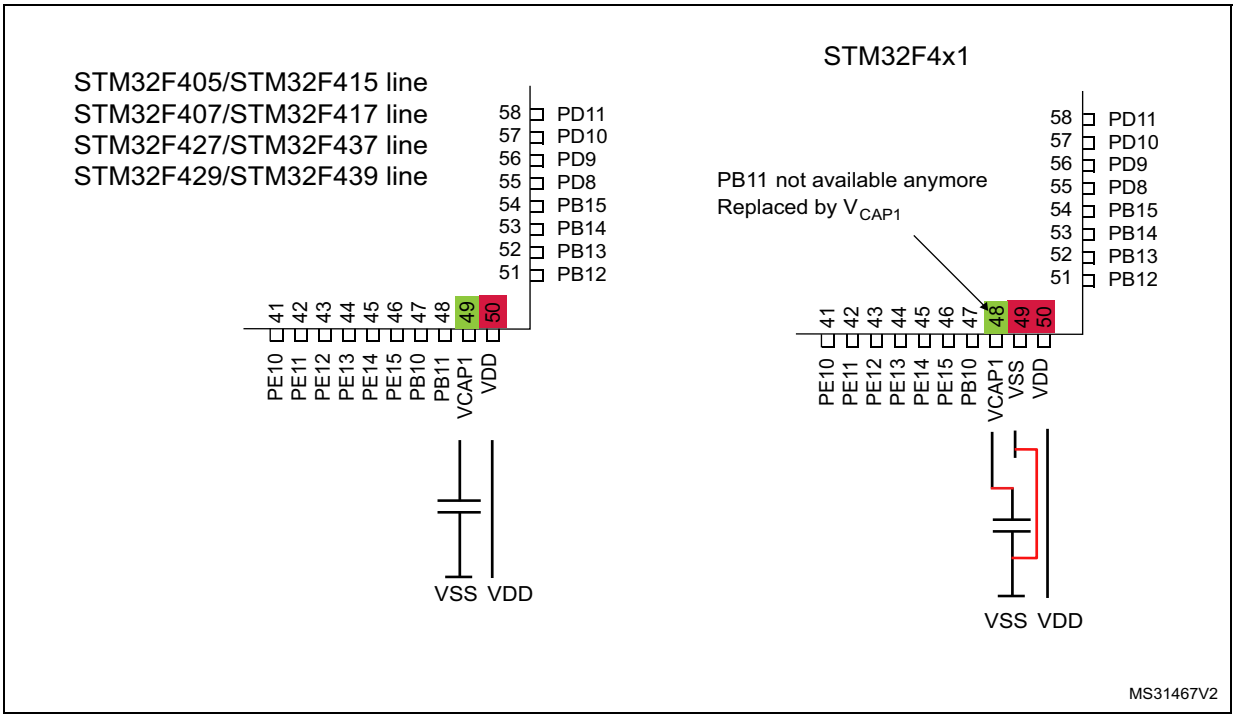


Table 6. USART feature comparison

USART name	Standard features	Modem (RTS/CTS)	LIN	SPI master	irDA	Smartcard (ISO 7816)	Max. baud rate in Mbit/s (oversampling by 16)	Max. baud rate in Mbit/s (oversampling by 8)	APB mapping
USART1	X	X	X	X	X	X	5.25	10.5	APB2 (max. 84 MHz)
USART2	X	X	X	X	X	X	2.62	5.25	APB1 (max. 42 MHz)
USART6	X	N.A	X	X	X	X	5.25	10.5	APB2 (max. 84 MHz)

3.22 Serial peripheral interface (SPI)

The devices feature up to four SPIs in slave and master modes in full-duplex and simplex communication modes. SPI1 and SPI4 can communicate at up to 42 Mbit/s, SPI2 and SPI3 can communicate at up to 21 Mbit/s. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC modes. All SPIs can be served by the DMA controller.

The SPI interface can be configured to operate in TI mode for communications in master mode and slave mode.

3.23 Inter-integrated sound (I^2S)

Two standard I^2S interfaces (multiplexed with SPI2 and SPI3) are available. They can be operated in master or slave mode, in full duplex and simplex communication modes and can be configured to operate with a 16-/32-bit resolution as an input or output channel. Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I^2S interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

All I^2Sx can be served by the DMA controller.

3.24 Audio PLL (PLLI2S)

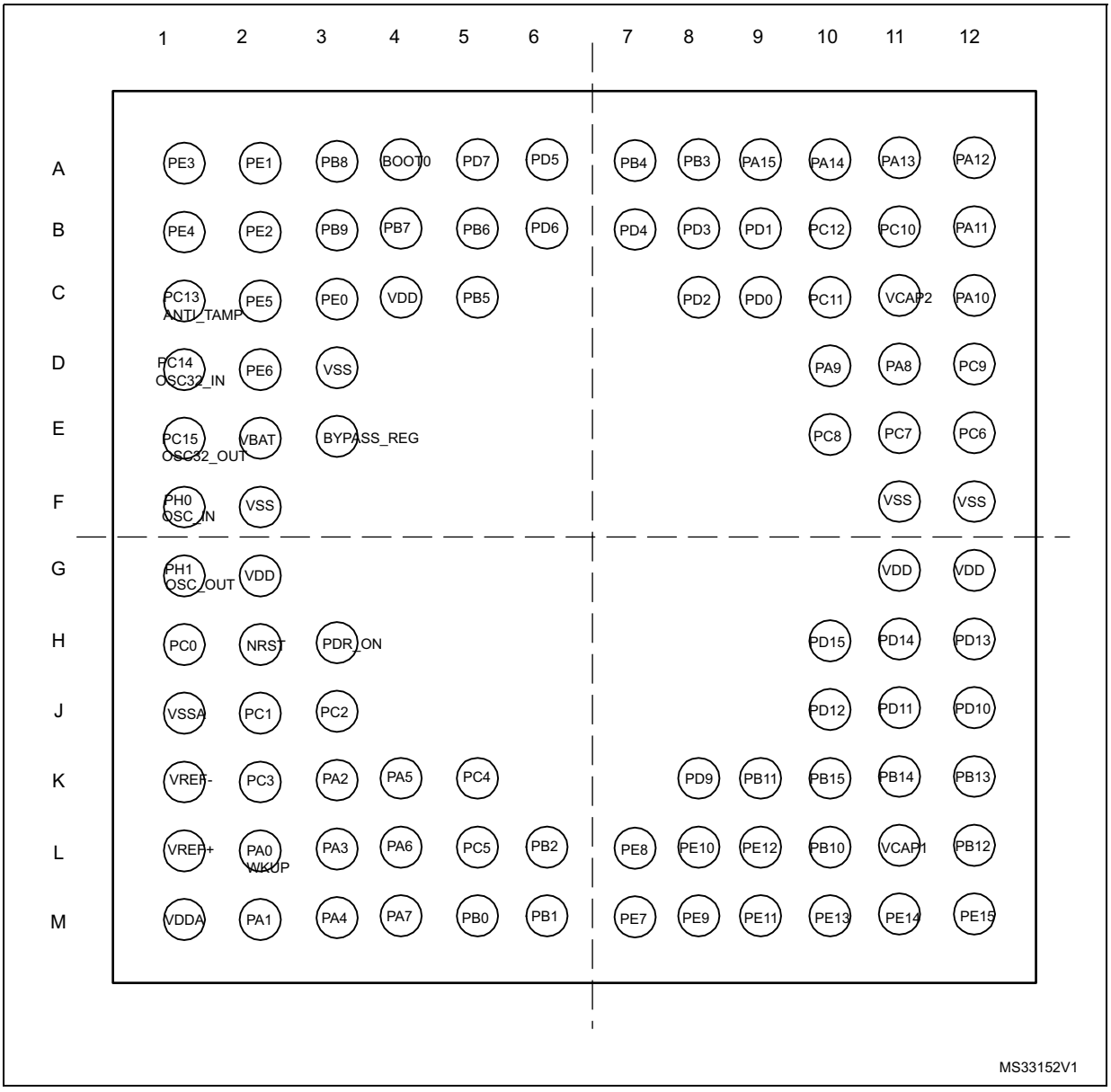
The devices feature an additional dedicated PLL for audio I^2S application. It allows to achieve error-free I^2S sampling clock accuracy without compromising on the CPU performance.

The PLLI2S configuration can be modified to manage an I^2S sample rate change without disabling the main PLL (PLL) used for the CPU.

The audio PLL can be programmed with very low error to obtain sampling rates ranging from 8 kHz to 192 kHz.

In addition to the audio PLL, a master clock input pin can be used to synchronize the I2S flow with an external PLL (or Codec output).

Figure 14. STM32F401xD/xE UFBGA100 pinout



1. This figure shows the package top view

Table 8. STM32F401xD/xE pin definitions (continued)

Pin Number					Pin name (function after reset)[1]	Pin type	I/O structure	Notes	Alternate functions	Additional functions
UQFN48	WLCSP49	LQFP64	LQFP100	UFBGA100						
-	-	-	45	M11	PE14	I/O	FT	-	SPI4_MOSI, TIM1_CH4, EVENTOUT	-
-	-	-	46	M12	PE15	I/O	FT	-	TIM1_BKIN, EVENTOUT	-
21	E3	29	47	L10	PB10	I/O	FT	-	SPI2_SCK/I2S2_CK, I2C2_SCL, TIM2_CH3, EVENTOUT	-
-	-	-	-	K9	PB11	I/O	FT	-	EVENTOUT	-
22	G2	30	48	L11	VCAP1	S	-	-	-	-
23	D3	31	49	F12	VSS	S	-	-	-	-
24	F2	32	50	G12	VDD	S	-	-	-	-
25	E2	33	51	L12	PB12	I/O	FT	-	SPI2_NSS/I2S2_WS, I2C2_SMBA, TIM1_BKIN, EVENTOUT	-
26	G1	34	52	K12	PB13	I/O	FT	-	SPI2_SCK/I2S2_CK, TIM1_CH1N, EVENTOUT	-
27	F1	35	53	K11	PB14	I/O	FT	-	SPI2_MISO, I2S2ext_SD, TIM1_CH2N, EVENTOUT	-
28	E1	36	54	K10	PB15	I/O	FT	-	SPI2_MOSI/I2S2_SD, TIM1_CH3N, EVENTOUT	RTC_REFIN
-	-	-	55	-	PD8	I/O	FT	-	EVENTOUT	-
-	-	-	56	K8	PD9	I/O	FT	-	EVENTOUT	-
-	-	-	57	J12	PD10	I/O	FT	-	EVENTOUT	-
-	-	-	58	J11	PD11	I/O	FT	-	EVENTOUT	-
-	-	-	59	J10	PD12	I/O	FT	-	TIM4_CH1, EVENTOUT	-
-	-	-	60	H12	PD13	I/O	FT	-	TIM4_CH2, EVENTOUT	-
-	-	-	61	H11	PD14	I/O	FT	-	TIM4_CH3, EVENTOUT	-
-	-	-	62	H10	PD15	I/O	FT	-	TIM4_CH4, EVENTOUT	-
-	-	37	63	E12	PC6	I/O	FT	-	I2S2_MCK, USART6_TX, TIM3_CH1, SDIO_D6, EVENTOUT	-
-	-	38	64	E11	PC7	I/O	FT	-	I2S3_MCK, USART6_RX, TIM3_CH2, SDIO_D7, EVENTOUT	-

Table 9. Alternate function mapping (continued)

Port		AF00	AF01	AF02	AF03	AF04	AF05	AF06	AF07	AF08	AF09	AF10	AF11	AF12	AF13	AF14	AF15
		SYS_AF	TIM1/TIM2	TIM3/ TIM4/ TIM5	TIM9/ TIM10/ TIM11	I2C1/I2C2/ I2C3	SPI1/SPI2/ I2S2/SPI3/ I2S3/SPI4	SPI2/I2S2/ SPI3/ I2S3	SPI3/I2S3/ USART1/ USART2	USART6	I2C2/ I2C3	OTG1_FS		SDIO			
Port B	PB0	-	TIM1_CH2N	TIM3_CH3	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB1	-	TIM1_CH3N	TIM3_CH4	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB3	JTDO-SWO	TIM2_CH2	-	-	-	SPI1_SCK	SPI3_SCK/ I2S3_CK	-	-	I2C2_SDA	-	-	-	-	-	EVENT OUT
	PB4	JTRST	-	TIM3_CH1	-	-	SPI1_ MISO	SPI3_MISO	I2S3ext_S D	-	I2C3_SDA	-	-	-	-	-	EVENT OUT
	PB5	-	-	TIM3_CH2	-	I2C1_ SMBA	SPI1 _MOSI	SPI3_MOSI/ I2S3_SD	-	-	-	-	-	-	-	-	EVENT OUT
	PB6	-	-	TIM4_CH1	-	I2C1_SCL	-	-	USART1_ TX	-	-	-	-	-	-	-	EVENT OUT
	PB7	-	-	TIM4_CH2	-	I2C1_SDA	-	-	USART1_ RX	-	-	-	-	-	-	-	EVENT OUT
	PB8	-	-	TIM4_CH3	TIM10_CH1	I2C1_SCL	-	-	-	-	-	-	-	SDIO_ D4	-	-	EVENT OUT
	PB9	-	-	TIM4_CH4	TIM11_CH1	I2C1_SDA	SPI2_NSS/I 2S2_WS	-	-	-	-	-	-	SDIO_ D5	-	-	EVENT OUT
	PB10	-	TIM2_CH3	-	-	I2C2_SCL	SPI2_SCK/I 2S2_CK	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB12	-	TIM1_BKIN	-	-	I2C2_ SMBA	SPI2_NSS/I 2S2_WS	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB13	-	TIM1_CH1N	-	-	-	SPI2_SCK/I 2S2_CK	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB14	-	TIM1_CH2N	-	-	-	SPI2_MISO	I2S2ext_SD	-	-	-	-	-	-	-	-	EVENT OUT
	PB15	RTC_ REFN	TIM1_CH3N	-	-	-	SPI2_MOSI /I2S2_SD	-	-	-	-	-	-	-	-	-	EVENT OUT

6.3 Operating conditions

6.3.1 General operating conditions

Table 14. General operating conditions

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HCLK}	Internal AHB clock frequency	Power Scale3: Regulator ON, VOS[1:0] bits in PWR_CR register = 0x01	0	-	60	MHz
		Power Scale2: Regulator ON, VOS[1:0] bits in PWR_CR register = 0x10	0	-	84	
f_{PCLK1}	Internal APB1 clock frequency		0	-	42	
f_{PCLK2}	Internal APB2 clock frequency		0	-	84	
V_{DD}	Standard operating voltage		1.7(1)	-	3.6	V
V_{DDA} (2)(3)	Analog operating voltage (ADC limited to 1.2 M samples)	Must be the same potential as V_{DD}(4)	1.7(1)	-	2.4	
	Analog operating voltage (ADC limited to 2.4 M samples)		2.4	-	3.6	
V_{BAT}	Backup operating voltage		1.65	-	3.6	
V_{12}	Regulator ON: 1.2 V internal voltage on V_{CAP_1}/V_{CAP_2} pins	VOS[1:0] bits in PWR_CR register = 0x01 Max frequency 60 MHz	1.08(5)	1.14	1.20(5)	
		VOS[1:0] bits in PWR_CR register = 0x10 Max frequency 84 MHz	1.20(5)	1.26	1.32(5)	
V_{12}	Regulator OFF: 1.2 V external voltage must be supplied on V_{CAP_1}/V_{CAP_2} pins	Max. frequency 60 MHz.	1.1	1.14	1.2	
		Max. frequency 84 MHz.	1.2	1.26	1.32	
V_{IN}	Input voltage on RST and FT pins(6)	$2\ V \leq V_{DD} \leq 3.6\ V$	–0.3	-	5.5	
		$V_{DD} \leq 2\ V$	–0.3	-	5.2	
	Input voltage on BOOT0 pin		0	-	9	
P_D	Maximum allowed package power dissipation for suffix 7(7)	UFQFPN48	-	-	625	mW
		WLCSP49	-	-	392	
		LQFP64	-	-	313	
		LQFP100	-	-	465	
		UFBGA100	-	-	323	

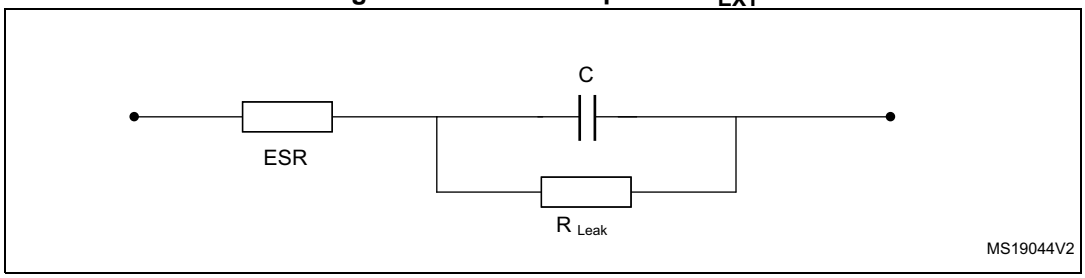
1. Applicable only when the code is executed from Flash memory. When the code is executed from RAM, no wait state is required.
2. Thanks to the ART accelerator and the 128-bit Flash memory, the number of wait states given here does not impact the execution speed from Flash memory since the ART accelerator allows to achieve a performance equivalent to 0 wait state program execution.
3. Refer to for frequencies vs. external load.
4. V_{DD}/V_{DDA} minimum value of 1.7 V, with the use of an external power supply supervisor (refer to *Section 3.14.2: Internal reset OFF*).
5. Prefetch is not available. Refer to AN3430 application note for details on how to adjust performance and power.
6. The voltage range for the USB full speed embedded PHY can drop down to 2.7 V. However the electrical characteristics of D- and D+ pins will be degraded between 2.7 and 3 V.

6.3.2 VCAP1/VCAP2 external capacitors

Stabilization for the main regulator is achieved by connecting external capacitor C_{EXT} to the VCAP1 and VCAP2 pin. For packages supporting only 1 VCAP pin, the 2 CEXT capacitors are replaced by a single capacitor.

C_{EXT} is specified in *Table 16*.

Figure 20. External capacitor C_{EXT}



1. Legend: ESR is the equivalent series resistance.

Table 16. VCAP1/VCAP2 operating conditions(1)

Symbol	Parameter	Conditions
CEXT	Capacitance of external capacitor with available VCAP1 and VCAP2 pins	2.2 µF
ESR	ESR of external capacitor with available VCAP1 and VCAP2 pins	< 2 Ω
CEXT	Capacitance of external capacitor with a single VCAP pin available	4.7 µF
ESR	ESR of external capacitor with a single VCAP pin available	< 1 Ω

1. When bypassing the voltage regulator, the two 2.2 µF V_{CAP} capacitors are not required and should be replaced by two 100 nF decoupling capacitors.

6.3.8 External clock source characteristics

High-speed external user clock generated from an external source

In bypass mode the HSE oscillator is switched off and the input pin is a standard I/O. The external clock signal has to respect the *Table 54*. However, the recommended clock input waveform is shown in *Figure 22*.

The characteristics given in *Table 35* result from tests performed using an high-speed external clock source, and under ambient temperature and supply voltage conditions summarized in *Table 14*.

Table 35. High-speed external user clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	External user clock source frequency(1)		1	-	50	MHz
V_{HSEH}	OSC_IN input pin high level voltage		$0.7V_{DD}$	-	V_{DD}	V
V_{HSEL}	OSC_IN input pin low level voltage		V_{SS}	-	$0.3V_{DD}$	
$t_{w(HSE)}$ $t_{w(HSE)}$	OSC_IN high or low time(1)		5	-	-	ns
$t_{r(HSE)}$ $t_{f(HSE)}$	OSC_IN rise or fall time(1)		-	-	10	
$C_{in(HSE)}$	OSC_IN input capacitance(1)		-	5	-	pF
$DuCy_{(HSE)}$	Duty cycle		45	-	55	%
I_L	OSC_IN Input leakage current	$V_{SS} \leq V_{IN} \leq V_{DD}$	-	-	±1	µA

1. Guaranteed by design, not tested in production.

Low-speed external user clock generated from an external source

In bypass mode the LSE oscillator is switched off and the input pin is a standard I/O. The external clock signal has to respect the *Table 54*. However, the recommended clock input waveform is shown in *Figure 23*.

The characteristics given in *Table 36* result from tests performed using an low-speed external clock source, and under ambient temperature and supply voltage conditions summarized in *Table 14*.

Figure 28 and *Figure 29* show the main PLL output clock waveforms in center spread and down spread modes, where:

F0 is f_{PLL_OUT} nominal.

T_{mode} is the modulation period.

md is the modulation depth.

Figure 28. PLL output clock waveforms in center spread mode

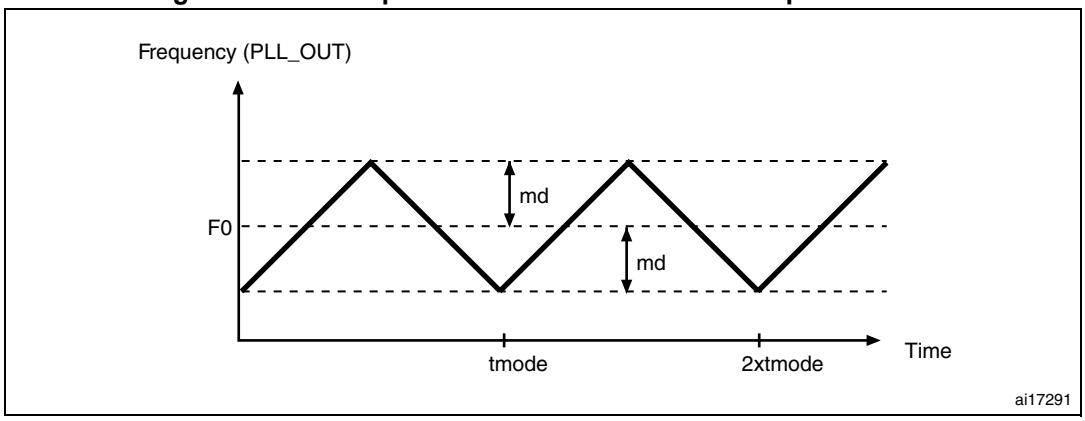
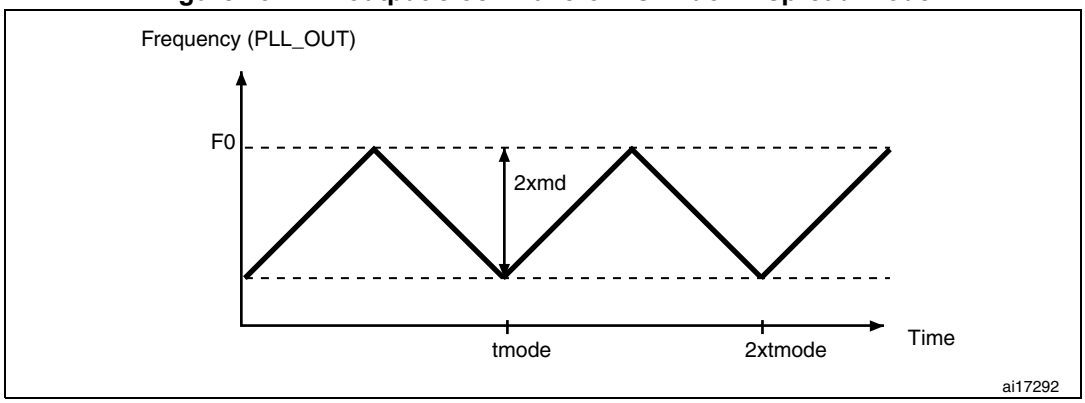


Figure 29. PLL output clock waveforms in down spread mode



6.3.12 Memory characteristics

Flash memory

The characteristics are given at T_A = –40 to 105 °C unless otherwise specified.

The devices are shipped to customers with the Flash memory erased.

Table 44. Flash memory characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_{DD}	Supply current	Write / Erase 8-bit mode, V_{DD} = 1.7 V	-	5	-	mA
		Write / Erase 16-bit mode, V_{DD} = 2.1 V	-	8	-	
		Write / Erase 32-bit mode, V_{DD} = 3.3 V	-	12	-	

Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application, executing EEMBC code, is running. This emission test is compliant with SAE IEC61967-2 standard which specifies the test board and the pin loading.

Table 49. EMI characteristics for WLCSP49

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f_{HSE}/f_{CPU}]	Unit
				8/84 MHz	
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A = 25 °C, conforming to IEC61967-2	0.1 to 30 MHz	-4	dBµV
			30 to 130 MHz	-4	
			130 MHz to 1 GHz	-2	
			SAE EMI Level	1.5	-

Table 50. EMI characteristics for LQFP100

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f_{HSE}/f_{CPU}]	Unit
				8/84 MHz	
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A = 25 °C, conforming to IEC61967-2	0.1 to 30 MHz	19	dBµV
			30 to 130 MHz	19	
			130 MHz to 1 GHz	11	
			SAE EMI Level	3.5	-

6.3.14 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

Table 51. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value(1)	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	T_A = +25 °C conforming to JESD22-A114	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	T_A = +25 °C conforming to ANSI/ESD STM5.3.1	II	400	

1. Guaranteed by characterization, not tested in production.

Static latchup

Two complementary static tests are required on six parts to assess the latchup performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latchup standard.

Table 52. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	T_A = +105 °C conforming to JESD78A	II level A

6.3.15 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard, 3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibilty to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (>5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of –5 µA/+0 µA range), or other functional failure (for example reset, oscillator frequency deviation).

Negative induced leakage current is caused by negative injection and positive induced leakage current by positive injection.

The test results are given in *Table 53*.

Table 55. Output voltage characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OL}(1)	Output low level voltage for an I/O pin	CMOS port(2) I_{IO} = +8 mA 2.7 V ≤ V_{DD} ≤ 3.6 V	-	0.4	V
V_{OH}(3)	Output high level voltage for an I/O pin		V_{DD}–0.4	-	
V_{OL} (1)	Output low level voltage for an I/O pin	TTL port(2) I_{IO} =+8 mA 2.7 V ≤ V_{DD} ≤ 3.6 V	-	0.4	V
V_{OH} (3)	Output high level voltage for an I/O pin		2.4	-	
V_{OL}(1)	Output low level voltage for an I/O pin	I_{IO} = +20 mA 2.7 V ≤ V_{DD} ≤ 3.6 V	-	1.3(4)	V
V_{OH}(3)	Output high level voltage for an I/O pin		V_{DD}–1.3(4)	-	
V_{OL}(1)	Output low level voltage for an I/O pin	I_{IO} = +6 mA 1.8 V ≤ V_{DD} ≤ 3.6 V	-	0.4(4)	V
V_{OH}(3)	Output high level voltage for an I/O pin		V_{DD}–0.4(4)	-	
V_{OL}(1)	Output low level voltage for an I/O pin	I_{IO} = +4 mA 1.7 V ≤ V_{DD} ≤ 3.6 V	-	0.4(5)	V
V_{OH}(3)	Output high level voltage for an I/O pin		V_{DD}–0.4(5)	-	

1. The I_{IO} current sunk by the device must always respect the absolute maximum rating specified in *Table 12*. and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VSS}.
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. The I_{IO} current sourced by the device must always respect the absolute maximum rating specified in *Table 12* and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VDD}.
4. Guaranteed by characterization results, not tested in production.
5. Guaranteed by design, not tested in production..

Input/output AC characteristics

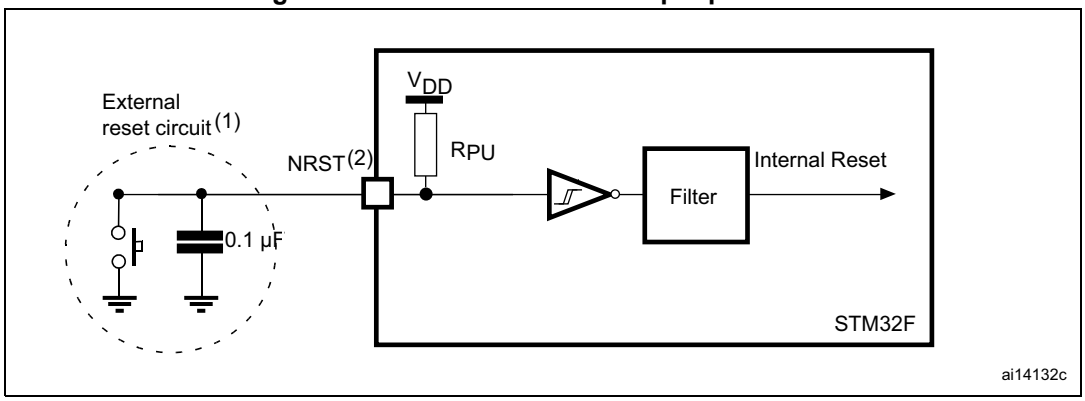
The definition and values of input/output AC characteristics are given in *Figure 31* and , respectively.

Unless otherwise specified, the parameters given in *Table 56* are derived from tests performed under the ambient temperature and V_{DD} supply voltage conditions summarized in *Table 14*.

Table 56. I/O AC characteristics(1)(2)

OSPEEDRy [1:0] bit value(1)	Symbol	Parameter	Conditions	Min	Typ	Max	Unit
00	$f_{max(IO)out}$	Maximum frequency(3)	C_L = 50 pF, V_{DD} ≥ 2.70 V	-	-	4	MHz
			C_L = 50 pF, V_{DD}≥ 1.7 V	-	-	2	
			C_L = 10 pF, V_{DD} ≥ 2.70 V	-	-	8	
			C_L = 10 pF, V_{DD} ≥ 1.7 V	-	-	4	
	$t_{f(IO)out}$/ $t_{r(IO)out}$	Output high to low level fall time and output low to high level rise time	C_L = 50 pF, V_{DD} = 1.7 V to 3.6 V	-	-	100	ns

Figure 32. Recommended NRST pin protection



1. The reset network protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the $V_{IL(NRST)}$ max level specified in *Table 57*. Otherwise the reset is not taken into account by the device.

6.3.18 TIM timer characteristics

The parameters given in *Table 58* are guaranteed by design.

Refer to *Section 6.3.16: I/O port characteristics* for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Table 58. TIMx characteristics(1)(2)

Symbol	Parameter	Conditions(3)	Min	Max	Unit
$t_{res(TIM)}$	Timer resolution time	AHB/APBx prescaler=1 or 2 or 4, $f_{TIMxCLK}$ = 84 MHz	1	-	$t_{TIMxCLK}$
			11.9	-	ns
		AHB/APBx prescaler>4, $f_{TIMxCLK}$ = 84 MHz	1	-	$t_{TIMxCLK}$
			11.9	-	ns
f_{EXT}	Timer external clock frequency on CH1 to CH4	$f_{TIMxCLK}$ = 84 MHz	0	$f_{TIMxCLK}/2$	MHz
			0	42	MHz
Res_{TIM}	Timer resolution		-	16/32	bit
$t_{COUNTER}$	16-bit counter clock period when internal clock is selected	$f_{TIMxCLK}$ = 84 MHz	0.0119	780	µs
t_{MAX_COUNT}	Maximum possible count with 32-bit counter		-	65536 × 65536	$t_{TIMxCLK}$
		$f_{TIMxCLK}$ = 84 MHz	-	51.1	S

1. TIMx is used as a general term to refer to the TIM1 to TIM11 timers.
2. Guaranteed by design, not tested in production.
3. The maximum timer frequency on APB1 is 42 MHz and on APB2 is up to 84 MHz, by setting the TIMPRE bit in the RCC_DCKCFGR register, if APBx prescaler is 1 or 2 or 4, then TIMxCLK = HCKL, otherwise TIMxCLK >= 4x PCLKx.

Figure 36. SPI timing diagram - master mode(1)

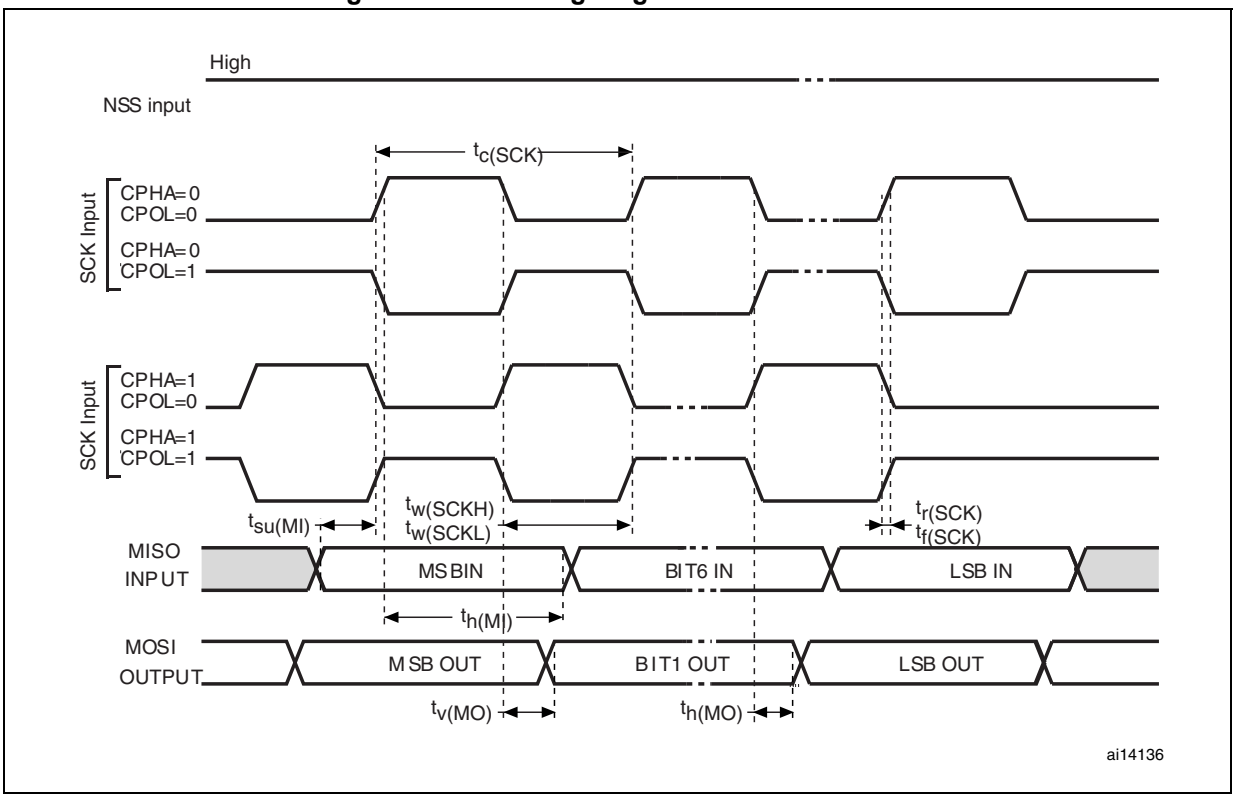
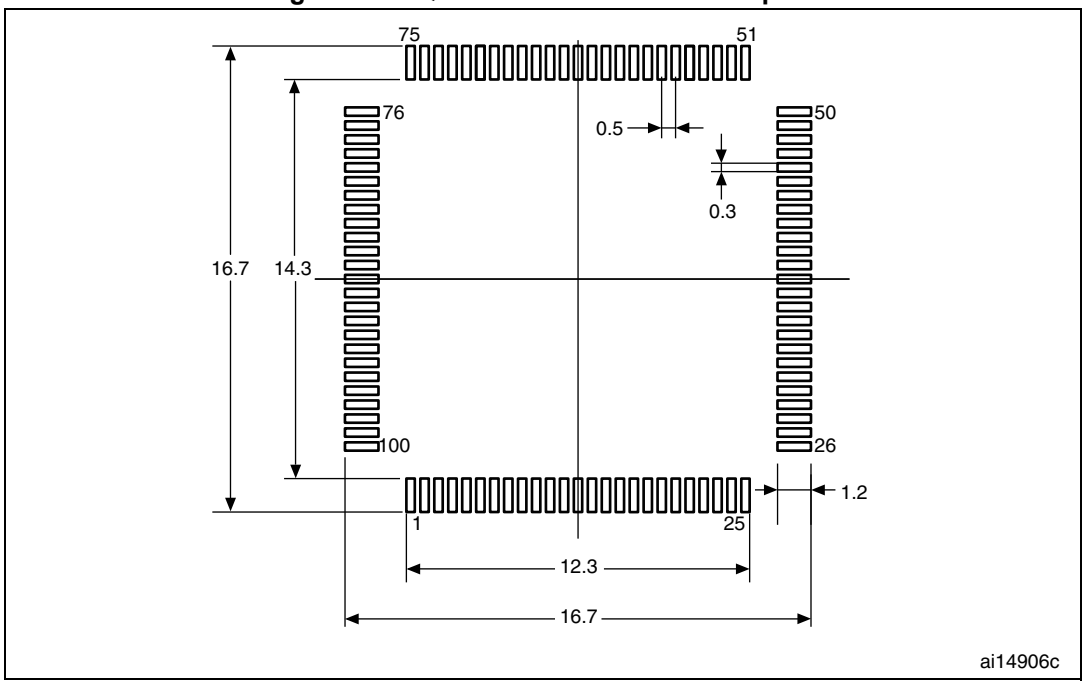


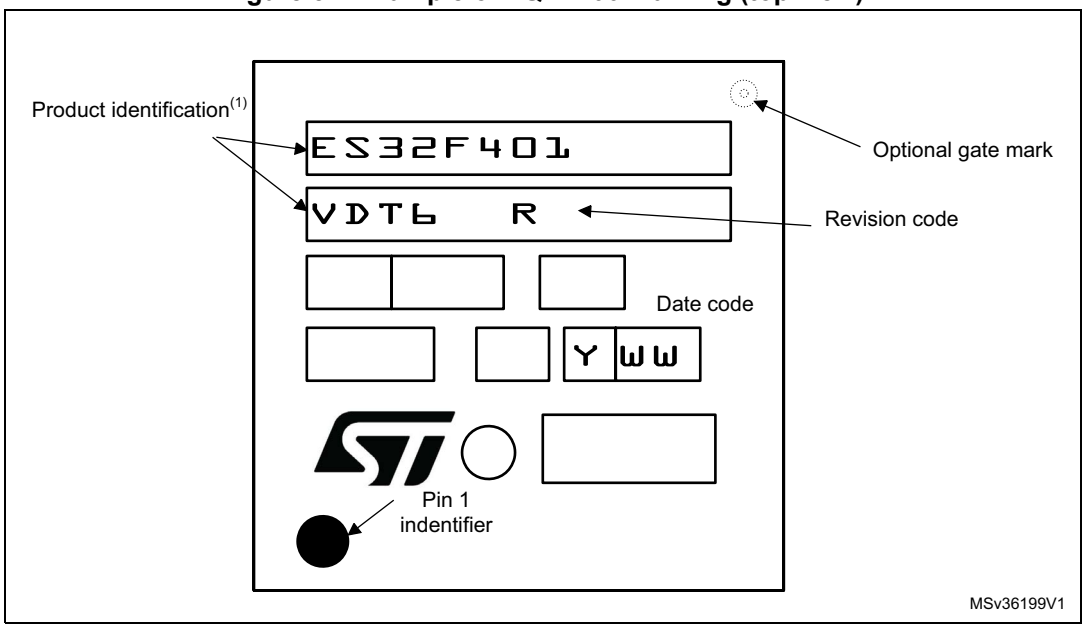
Figure 56. LQFP100 recommended footprint



1. Dimensions are in millimeters.

Device marking

Figure 57. Example of LQPF100 marking (top view)



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

7.2 Thermal characteristics

The maximum chip junction temperature ($T_J$max) must never exceed the values given in *Table 14: General operating conditions on page 60*.

The maximum chip-junction temperature, T_J max., in degrees Celsius, may be calculated using the following equation:

T_J max = T_A max + (PD max x Θ_{JA})

Where:

- T_A max is the maximum ambient temperature in °C,
- Θ_{JA} is the package junction-to-ambient thermal resistance, in °C/W,
- PD max is the sum of P_{INT} max and $P_{I/O}$ max (PD max = P_{INT} max + $P_{I/O}$max),
- P_{INT} max is the product of I_{DD} and V_{DD}, expressed in Watts. This is the maximum chip internal power.

$P_{I/O}$ max represents the maximum power dissipation on output pins where:

$$P_{I/O} \text{ max} = \Sigma (V_{OL} \times I_{OL}) + \Sigma((V_{DD} - V_{OH}) \times I_{OH}),$$

taking into account the actual V_{OL} / I_{OL} and V_{OH} / I_{OH} of the I/Os at low and high level in the application.

Table 85. Package thermal characteristics

Symbol	Parameter	Value	Unit
Θ_{JA}	**Thermal resistance junction-ambient** UFQFPN48	32	°C/W
	Thermal resistance junction-ambient WLCSP49	51	
	Thermal resistance junction-ambient LQFP64	50	
	Thermal resistance junction-ambient LQFP100	42	
	Thermal resistance junction-ambient UFBGA100	56	

7.2.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from www.jedec.org.

Table 87. Device order codes

Reference	Order codes
STM32F401xD	STM32F401CDY6, STM32F401RDT6, STM32F401VDT6, STM32F401CDU6, STM32F401VDH6
STM32F401xE	STM32F401CEY6, STM32F401RET6, STM32F401VET6, STM32F401CEU6, STM32F401VEH6